

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application: Wagdi Abadeer et al

Date: December 9, 2003

Serial No.: Unknown

Group Art Unit: 2818

Filed: Herewith

Examiner: Nguyen, Dao H.

Title: TEST STRUCTURE AND METHODOLOGY
FOR SEMICONDUCTOR STRESS-INDUCED
DEFECTS AND ANTIFUSE BASED ON
SAME TEST STRUCTURE

Docket: BUR920010031US3

PRELIMINARY AMENDMENT UNDER 37 CFR 111

To the Assistant Commissioner of Patents

Washington, D.C. 20231

Dear Sir:

Prior to examination, please enter the following Preliminary Amendment for the patent application identified above.

Certificate of Mailing by Express Mail Label Number EL046035730US	
I certify that this document and fee is being deposited with the United States Post Office as Express Mail under 37 C.F.R. 1.110 and is addressed to the Assistant Commissioner of Patents, Washington, D.C. Alexandria, VA. 22313/450	
Date <u>12-9-03</u>	<u>Deborah S. Drury</u> Print name of Person signing document <u>Deborah S. Drury</u>